

# **PSEC2**

## Results and further testing plans

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Electronics Godparent Review 10/5/2010

# PSEC-2 2<sup>nd</sup> gen fast “oscilloscope on a chip”

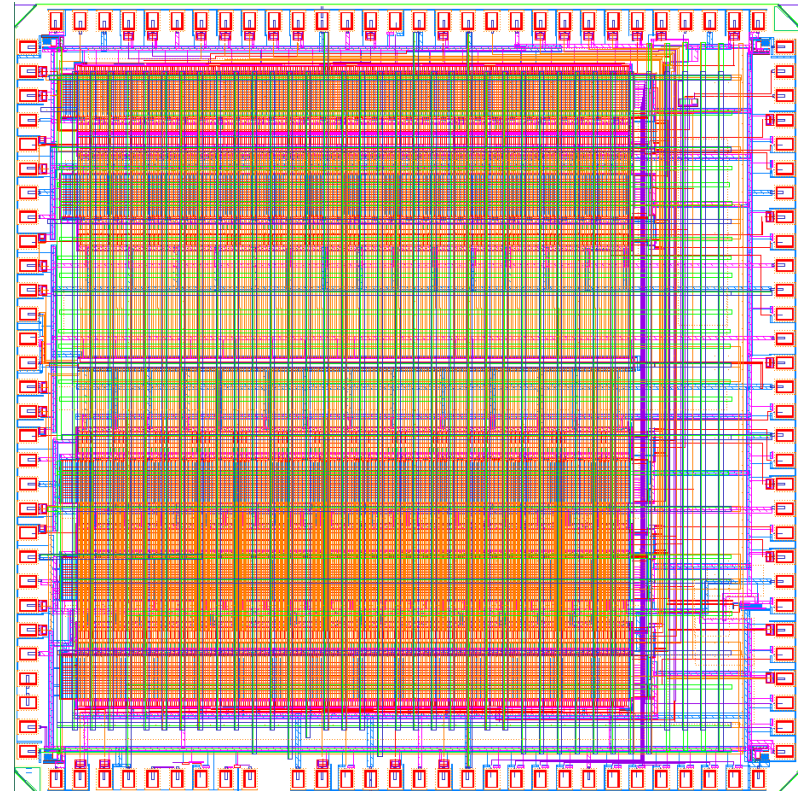
## target specs

- channels: 4
- sampling rate: 5-18 GS/s
- sampling depth: 256
- input bandwidth: ~ 2GHz
- dynamic range: 1V
- A/D conversion: 12 bits in 2  $\mu$ s  
8 bits in 130 ns
- readout: 6  $\mu$ s/channel
- power: <100mW/channel
- Internal trigger

## process

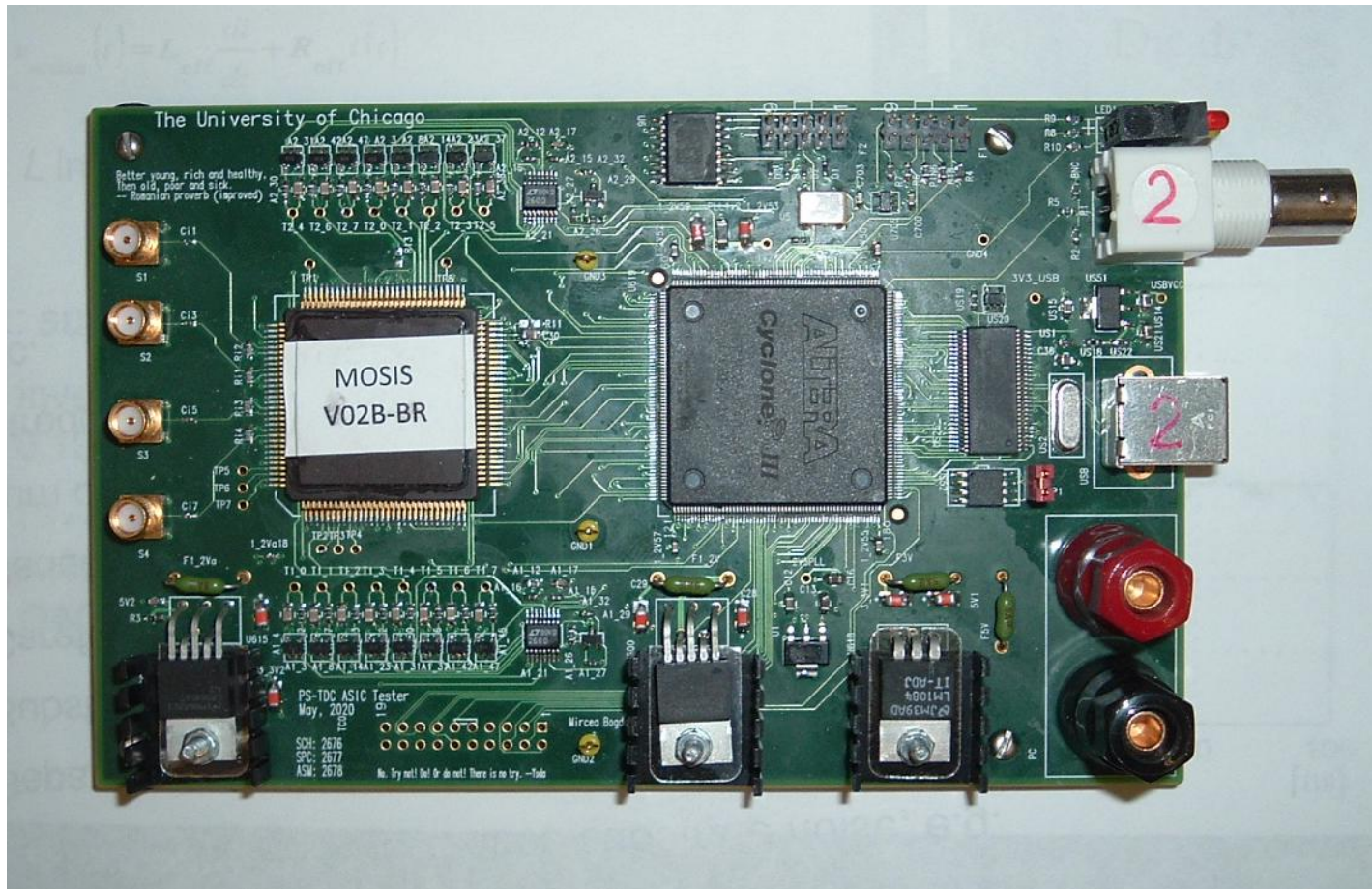
- IBM 130 nm CMOS
- submitted directly to MOSIS
- chip back: June 2010

## layout



area: 4.4x4.4 mm<sup>2</sup>

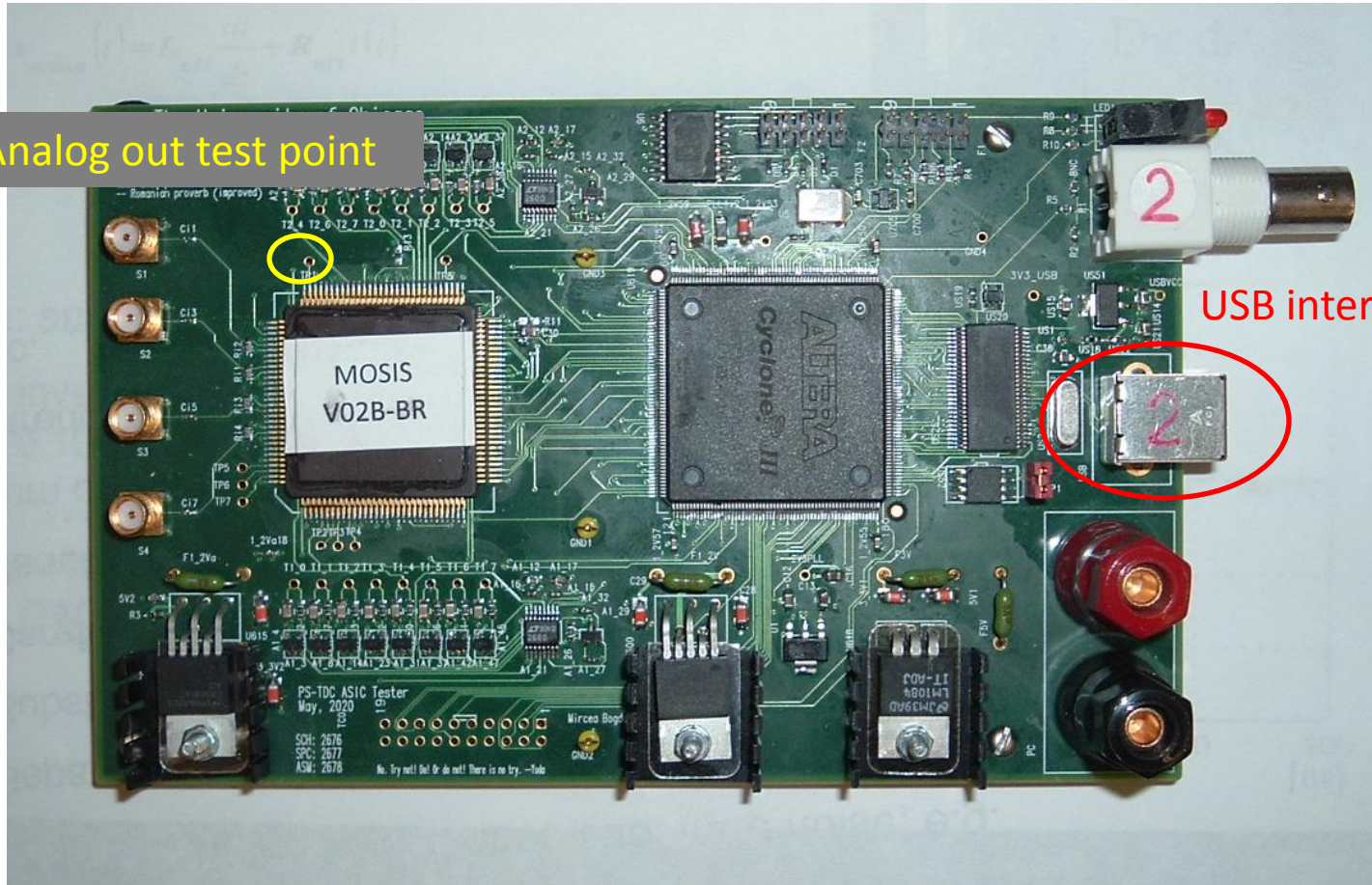
# PSEC2 Eval Board





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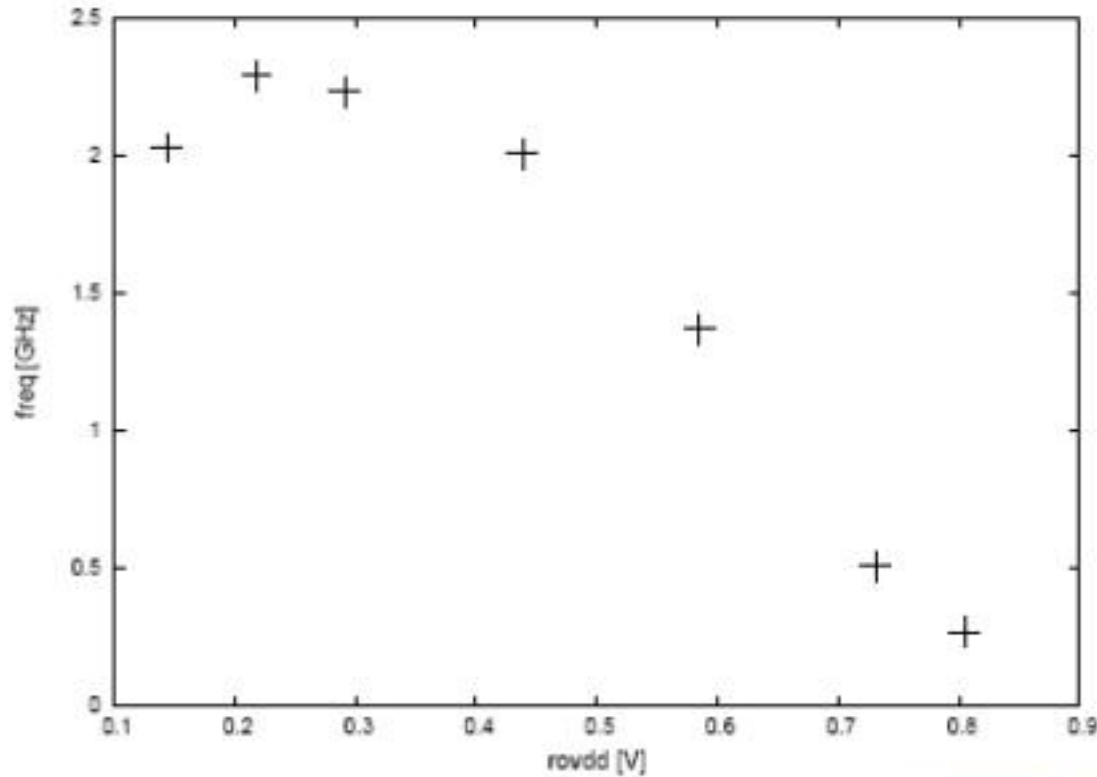
Chan 1 Analog out test point



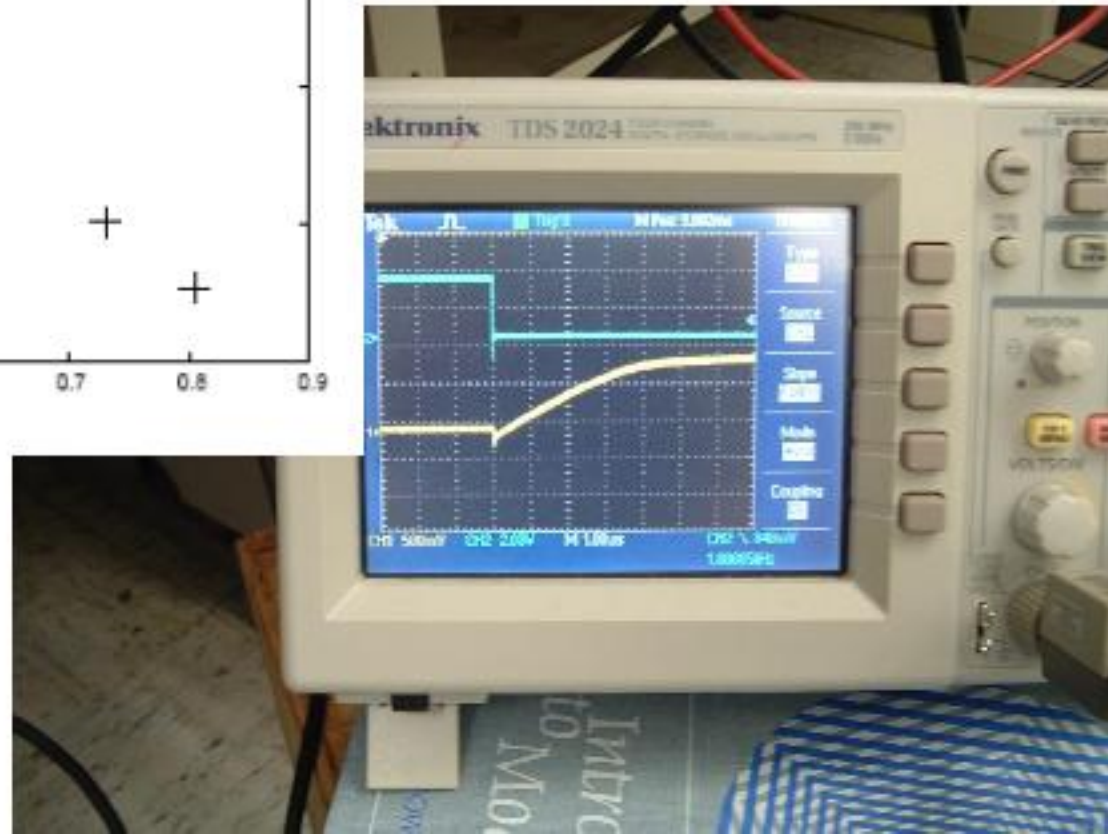
USB interface

# ADC Test points

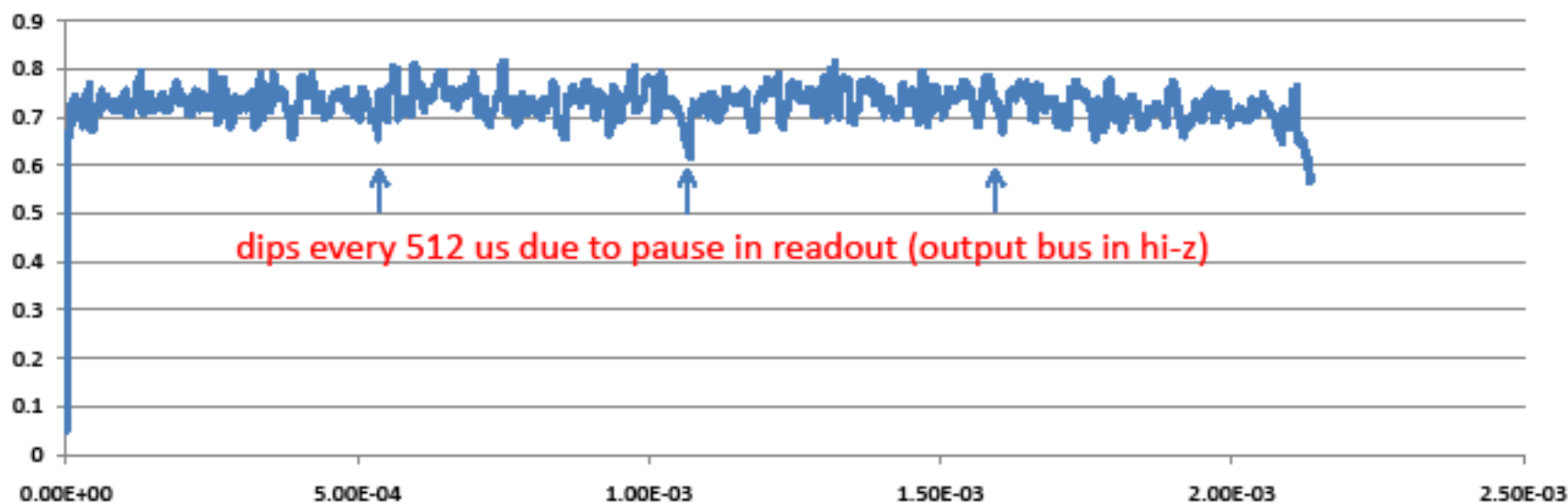
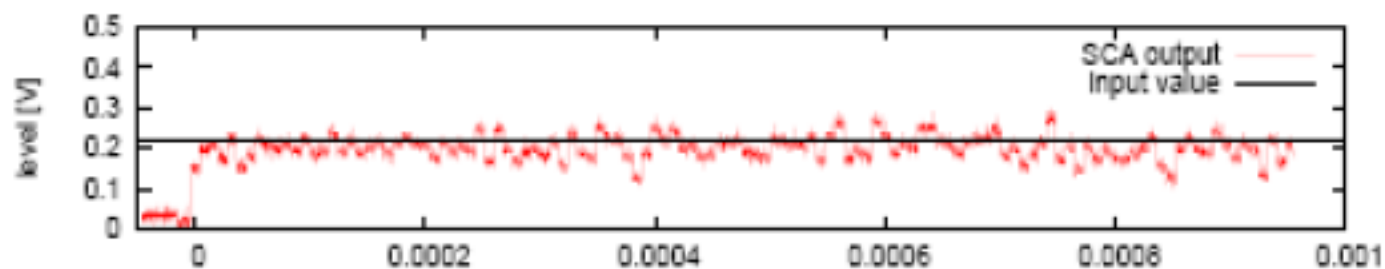
Ring Oscillator – digitization speed



Ramp generation



## Channel 1 – Analog out (DC level)



Sampling rate: 5GS/s

readout speed: 125KHz (8 us/cell)

# Digitization: having problems w/ Wilkinson ADC

read clock

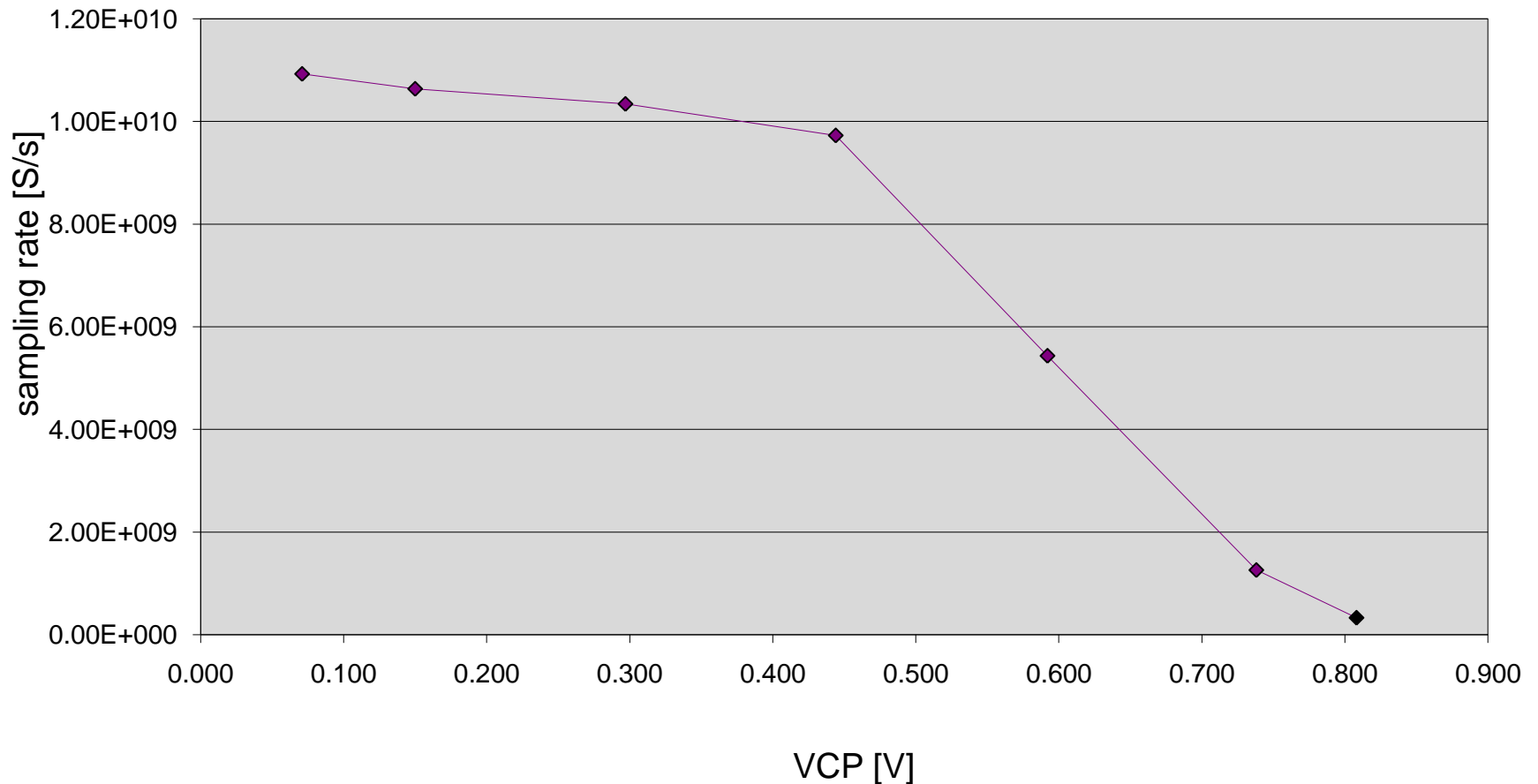
tok in

tok out

Some bits appeared to still be counting once counter is stopped – leakage developed after several microseconds of storage . Simulations confirmed that dynamic dff in ADC counters leaks.

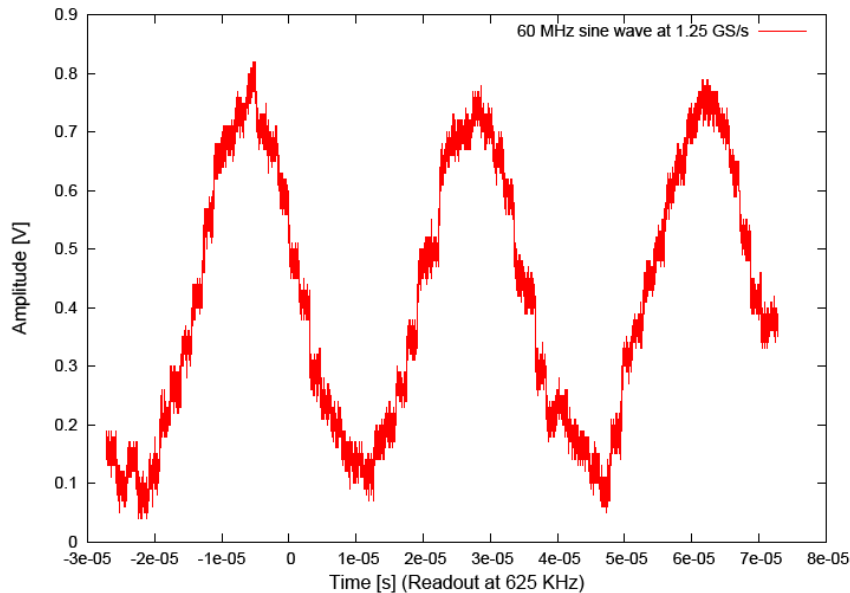
# Sampling speed measurement:

Using sine wave input to chan1, used the analog out option to measure the sampling rate (topping out ~11 GS/s)

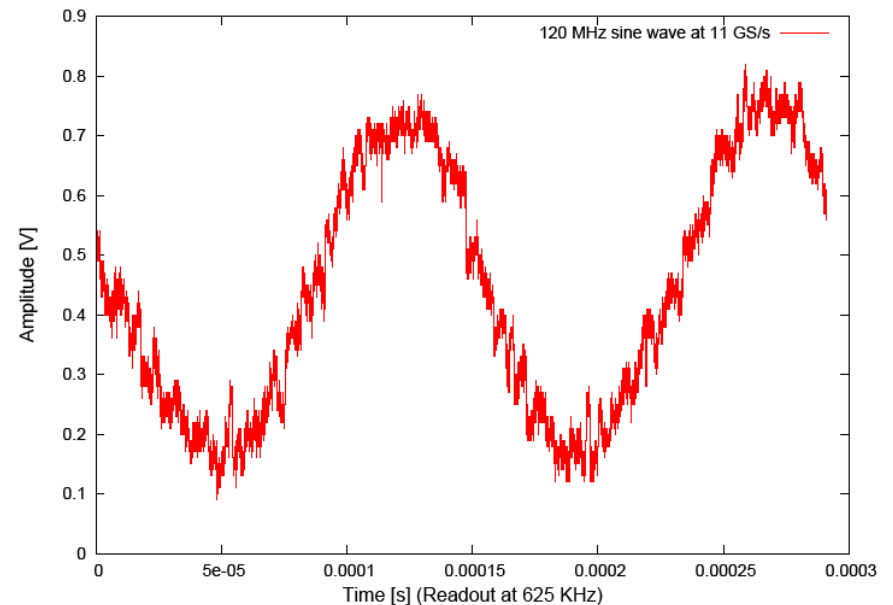




# Sampled waveforms using Analog-out



1.25 GS/s



11 GS/s

Notes: Analog values are stored on buffer input capacitance, not designated sampling capacitor. (due to error in schematic)

Noise seen here dominated by set-up (scope, probe, etc.). We are currently designing board with external ADC to better characterize the noise/bandwidth

## Summary

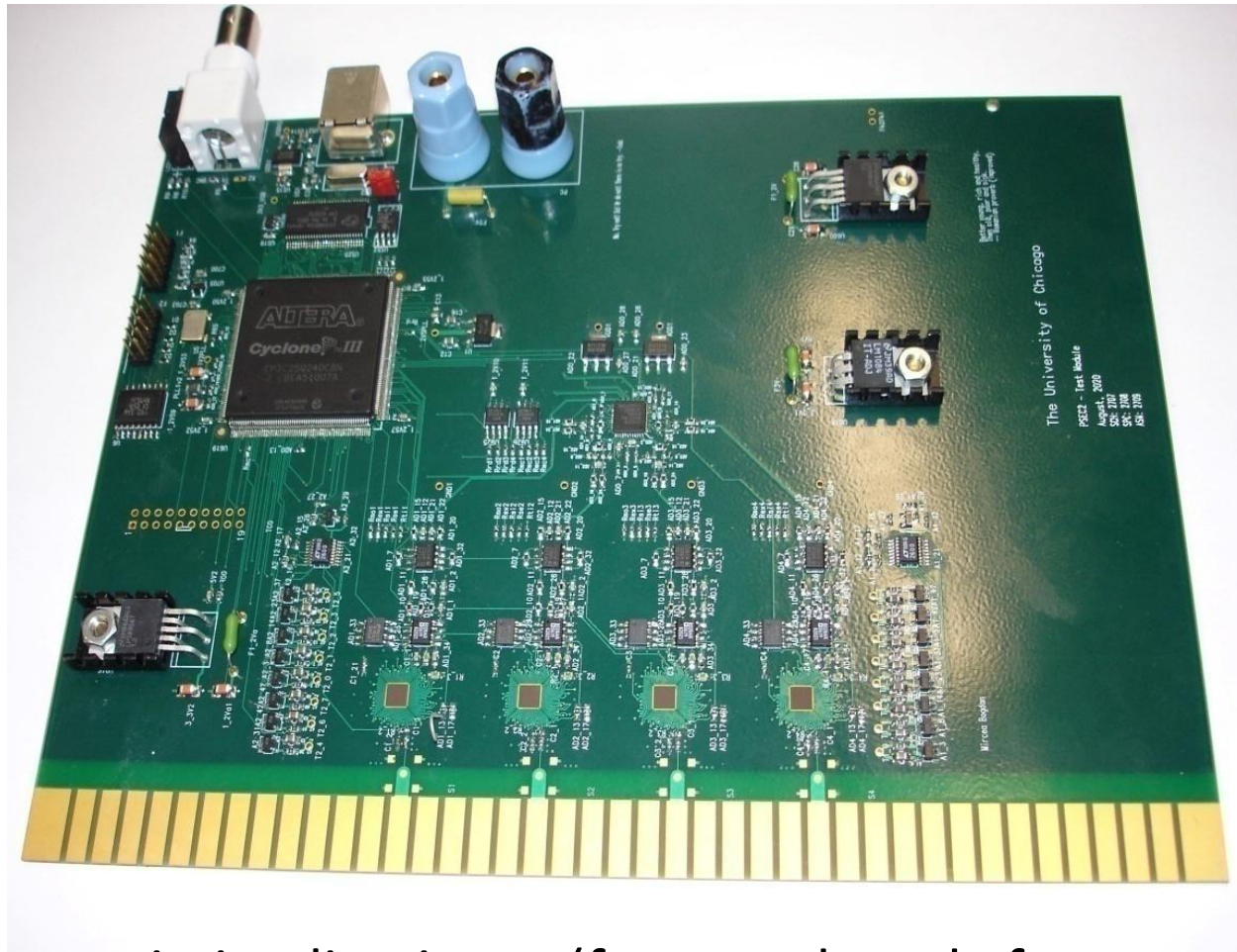
working: timing, sampling (mostly), readout, ramp

not working: A/D

## Plans

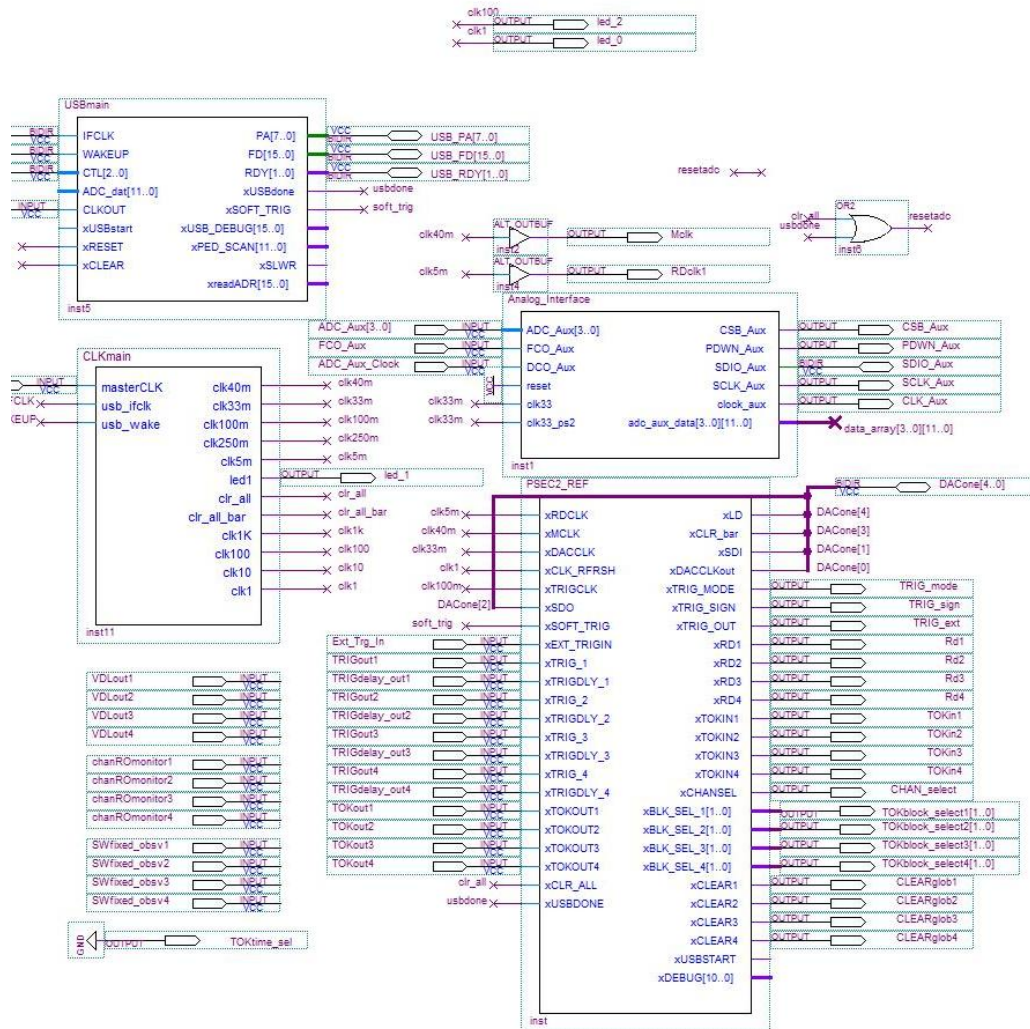
Possibly design a board with external ADC for use with Chan1 analog-out. This would allow for further chip characterization (noise and bandwidth in particular).

# PSEC2 flip chip/external ADC Eval Board



Transmission line input (front-end ready for large-area MCP tray)

# PSEC2 flip chip/external ADC Eval Board

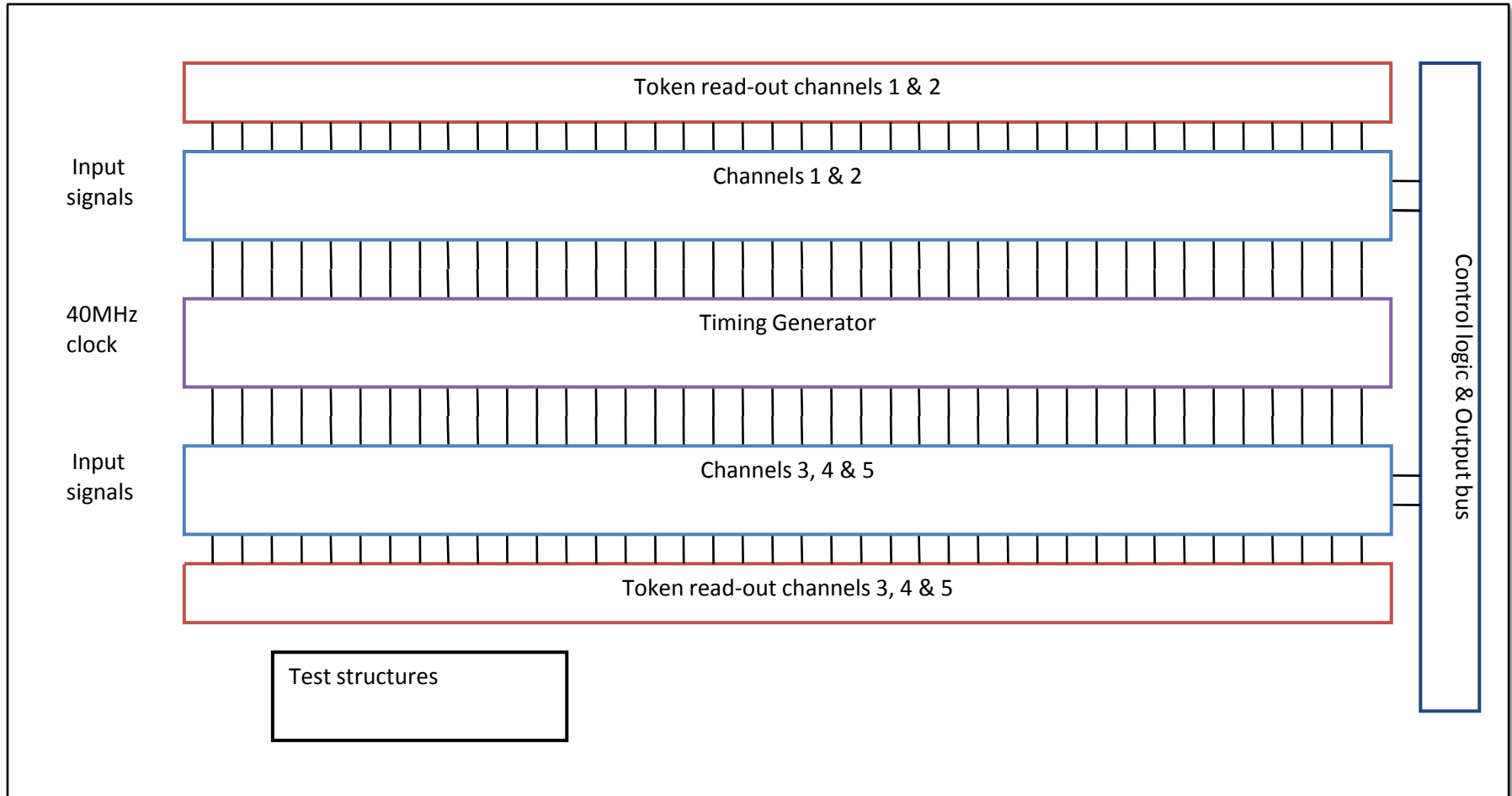


- Firmware basically done
- board was tested in the last few days. Everything seems ok
- proceed with stud bonding of bare PSEC2s. (4x2 boards)
- Finish PSEC2 tests in next weeks...move on

backup

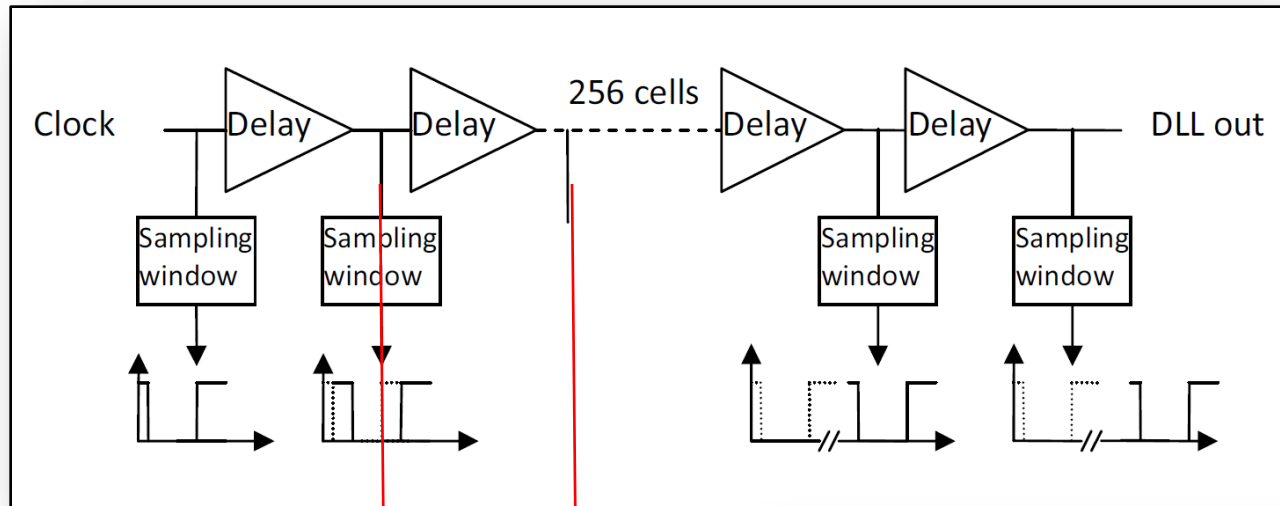


# Principle of Operation



block diagram

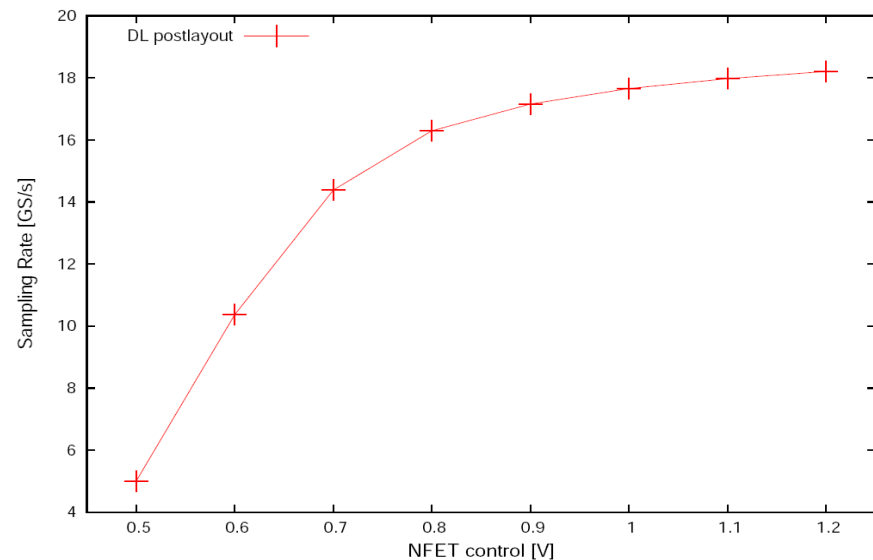
# Principle of Operation - timing generator



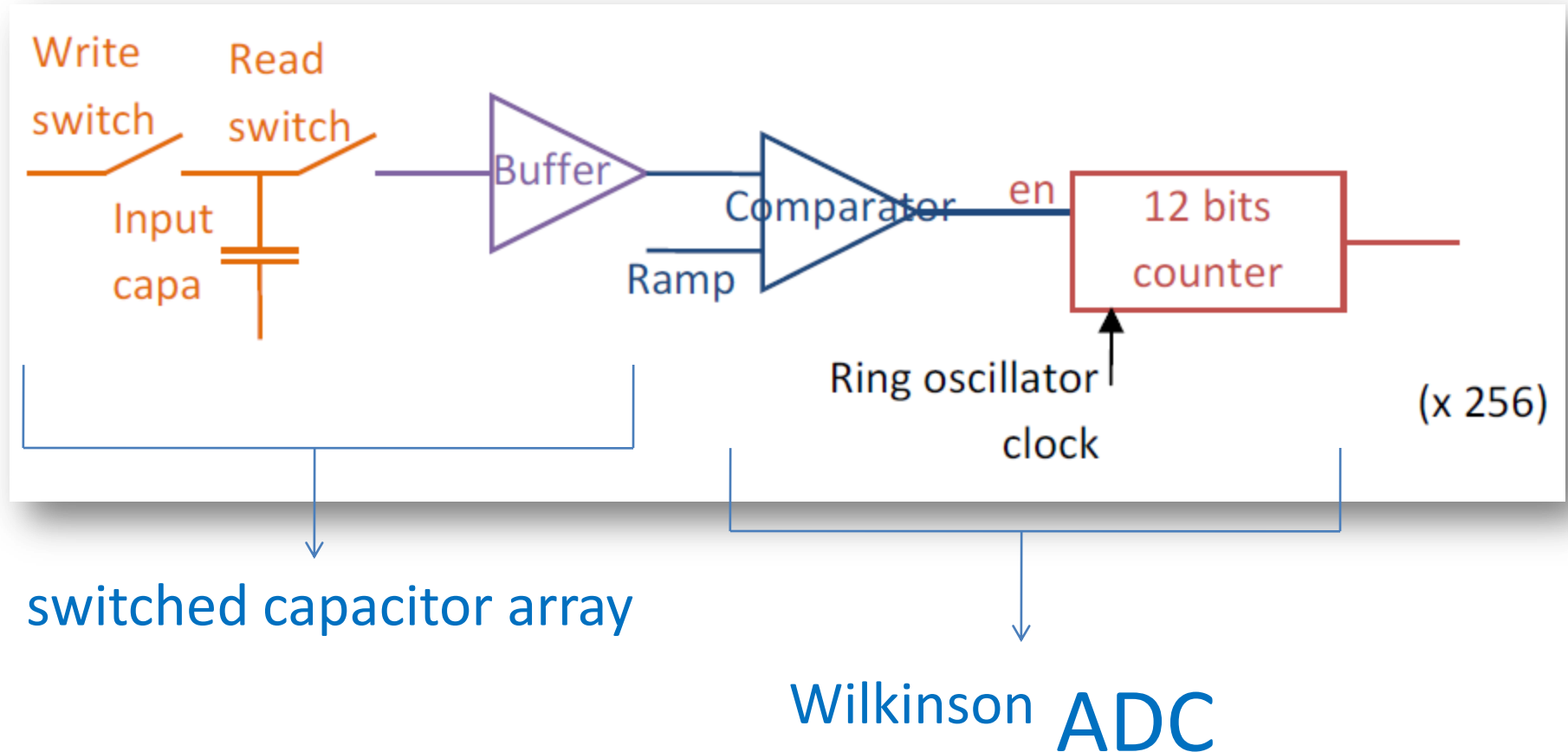
voltage-controlled  
delay line

delay per cell:  $\Delta t$

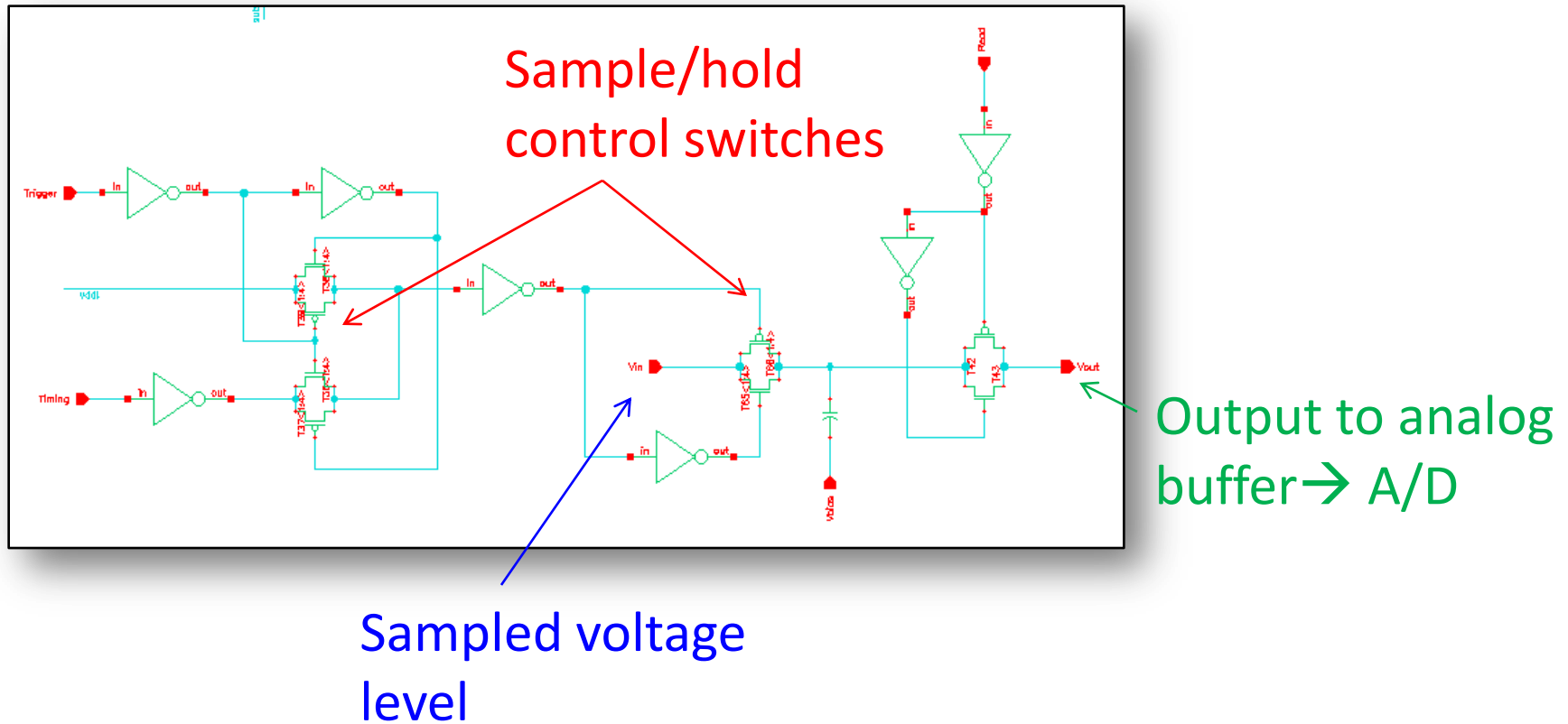
Sampling rate =  $1/\Delta t$



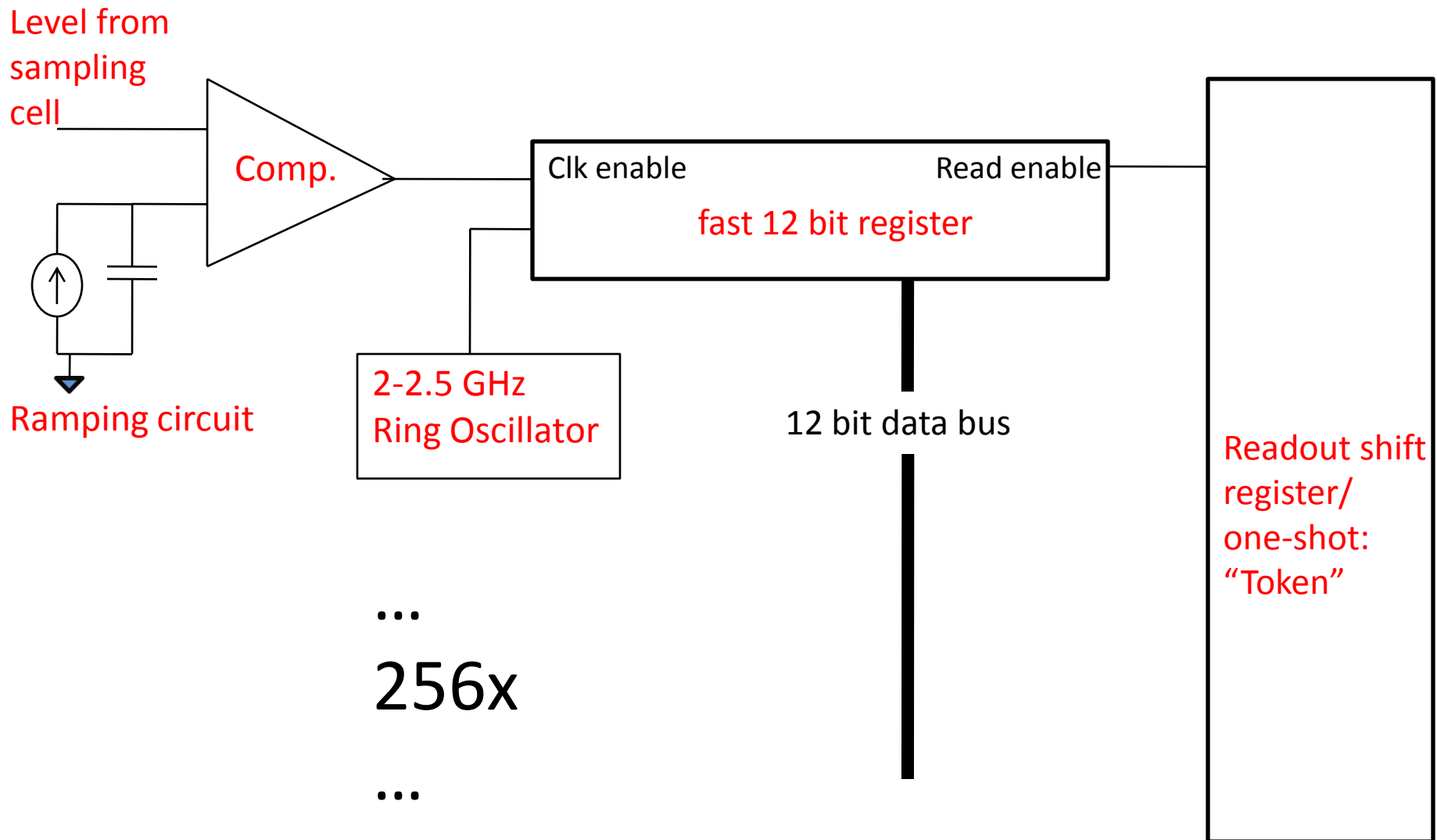
# Principle of Operation – channel block diagram



# Principle of Operation – switched cap circuit

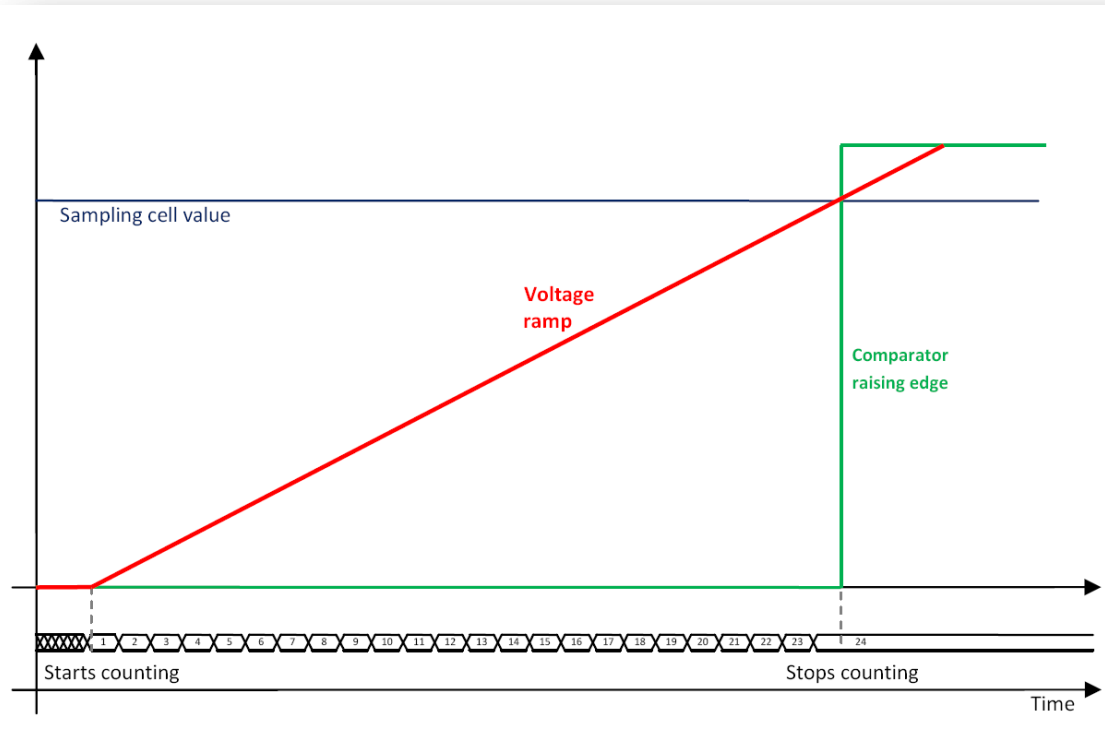


# Principle of Operation – ADC & Readout





# Principle of Operation – ADC & Readout



A/D conversion ↑

Token readout →

